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Application Number

10/823,098

Filing Date

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First Named Inventor

Kowang Liu et al.

Art Unit

3744

Examiner Name

L.V. Ciric

Attorney Docket Number

HT03-026CC

NON PATENT LITERATURE DOCUMENTS

| Examiner Initials* | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T ² |
|-----------------------|--------------------------|---|----------------|
| /LC/ | 1 | "Thermal Conductivity of AlN and SiC Thin Films," by SUN ROCK CHOI ET AL., International Journal of Thermophysics, ISSN 0195-928X, 2006, | |
| | | Vol. 27, No. 3. pp. 896-905, Springer, New York, NY. | |
| | 2 | "Measurement of the thermal conductivity of TiO ₂ thin films by using the thermo-reflectance method," by JUNGHO MUN ET AL., ScienceDirect - | |
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| | 3 | "Thermal conductivity measurements on thin films based on micromechanical devices," by E. JANSEN ET AL., Journal of Micromechanics | |
| | | and Microengineering, Vol. 6, 1996, http://www.iop.org/EJ/abstract/0960-1317/6/1/029 . | |
| | 4 | "Electrical properties," and "Thermal conductivity," page 5 of 9, found: http://en.wikipedia.org/wiki/Material_properties_of_diamond#Thermal_conductivity , | |
| /LC/ | | Material properties of diamond - Wikipedia, the free encyclopedia, 1/18/09. | |
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Examiner
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